



Designation: ~~E1316--22~~ E1316 – 22a

## Standard Terminology for Nondestructive Examinations<sup>1</sup>

This standard is issued under the fixed designation E1316; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon ( $\epsilon$ ) indicates an editorial change since the last revision or reapproval.

### INDEX OF TERMS

#### Section

A:	Common NDT Terms
B:	Acoustic Emission (AE) Terms
C:	Electromagnetic Testing (ET) Terms
D:	Gamma- and X-Radiologic Testing (RT) Terms
E:	Leak Testing (LT) Terms
F:	Liquid Penetrant Testing (PT) Terms
G:	Magnetic Particle Testing (MT) Terms
H:	Neutron Radiologic Testing (NRT) Terms
I:	Ultrasonic Testing (UT) Terms
J:	Infrared Testing (IRT) Terms
K:	Optical Holographic Testing (HT) Terms
L:	Visual Testing (VT) Terms

### 1. Scope

1.1 This standard defines the terminology used in the standards prepared by the E07 Committee on Nondestructive Testing. These nondestructive testing (NDT) methods include: acoustic emission, electromagnetic testing, gamma- and X-radiology, leak testing, liquid penetrant testing, magnetic particle testing, neutron radiology and gauging, ultrasonic testing, and other technical methods.

1.2 Committee E07 recognizes that the terms examination, testing, and inspection are commonly used as synonyms in nondestructive testing. For uniformity and consistency in E07 nondestructive testing standards, Committee E07 encourages the use of the terms examination or inspection and their derivatives when describing the application of nondestructive test methods. In a specific standard, either examination or inspection shall be used consistently throughout the document. Similarly, E07 encourages the use of the term test and its derivatives when referring to the body of knowledge of a nondestructive testing method. There are, however, appropriate exceptions when the term test and its derivatives may be used to describe the application of a nondestructive test, such as measurements which produce a numeric result (for example, when using the leak testing method to perform a leak test on a component, or an ultrasonic measurement of velocity). Additionally, the term test should be used when referring to the NDT method, that is, Radiologic Testing (RT), Ultrasonic Testing (UT), and so forth. (Example: Radiologic Testing (RT) is often used to examine material to detect internal discontinuities.)

NOTE 1—The following sentences clarify this policy and illustrate its use:

- (a) Nondestructive testing methods are used extensively for the examination or inspection of materials and components.
- (b) The E07 Committee on Nondestructive Testing has prepared many documents to promote uniform usage of the nondestructive testing methods that are applied to examine or inspect materials and components.
- (c) Radiologic Testing (RT) is often used to inspect material to detect internal discontinuities.
- (d) Magnetic Particle Testing (MT), Liquid Penetrant Testing (PT), and Visual Testing (VT) are often used to examine the surface of a component.

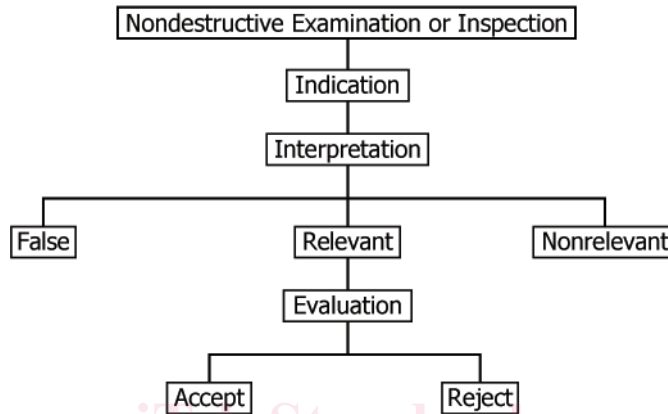
<sup>1</sup> This terminology is under the jurisdiction of ASTM Committee E07 on Nondestructive Testing and is the direct responsibility of Subcommittee E07.92 on Editorial Review.

Current edition approved Feb. 1, 2022; June 1, 2022. Published February 2022; June 2022. Originally approved in 1989. Last previous edition approved in 2024 as E1316 – 21 and E1316 – 22. DOI: 10.1520/E1316-22.10.1520/E1316-22A.

- (e) The Bubble Leak Testing (BLT) method is sometimes used to leak test a pressure containing component to detect leaks.
- (f) A guide for Nondestructive Testing of additively manufactured materials will describe several methods but a practice will focus on a single inspection method.

1.3 Section A defines terms that are common to multiple NDT methods, whereas the subsequent sections define terms pertaining to specific NDT methods.

1.4 As shown on the chart below, when a nondestructive examination or inspection produces an indication, the indication is subject to interpretation as false, nonrelevant, or relevant. If it has been interpreted as relevant, the necessary subsequent evaluation will result in the decision to accept or reject the material. With the exception of accept and reject, which retain the meaning found in most dictionaries, all the words used in the chart are defined in Section A.



1.5 This international standard was developed in accordance with internationally recognized principles on standardization established in the Decision on Principles for the Development of International Standards, Guides and Recommendations issued by the World Trade Organization Technical Barriers to Trade (TBT) Committee.

**2. Referenced Documents**

2.1 *ASTM Standards:*<sup>2</sup>

- E94 Guide for Radiographic Examination Using Industrial Radiographic Film
- E1106 Test Method for Primary Calibration of Acoustic Emission Sensors
- E1781 Practice for Secondary Calibration of Acoustic Emission Sensors

NOTE 2—This standard defines the terminology used in the standards prepared by Committee E07 on Nondestructive Testing and published in the *Annual Book of ASTM Standards*, Volumes 03.03 and 03.04.

**3. Significance and Use**

3.1 The terms found in this standard are intended to be used uniformly and consistently in all nondestructive testing standards. The purpose of this standard is to promote a clear understanding and interpretation of the NDT standards in which they are used.

**4. Terminology**

4.1 *Definitions*—The definitions provided below have been broken up into sections; each section is arranged in alphabetical order.

**Section A: Common NDT Terms**

The terms defined in Section A are the direct responsibility of Subcommittee E07.92, Editorial Review.

**acceptable quality level**—the maximum percent defective or the maximum number of units defective per hundred units that, for the purpose of sampling test, can be considered satisfactory as a process average.

<sup>2</sup> For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard’s Document Summary page on the ASTM website.

**calibration, instrument, *n***—the comparison of an instrument with, or the adjustment of an instrument to, a known reference(s) often traceable to the National Institute of Standards and Technology (NIST). (See also **standardization, instrument.**)

**cognizant engineering organization**—the company, government agency or other authority responsible for the design, or end use, of the material or component for which nondestructive testing is required.

**DISCUSSION—**

In addition to design personnel, the cognizant engineering organization could include personnel from engineering, material and process engineering, stress analysis, nondestructive testing, quality assurance and others, as appropriate.

**defect, *n***—one or more flaws whose aggregate size, shape, orientation, location, or properties do not meet specified acceptance criteria and are rejectable.

**Digital Imaging and Communication for Nondestructive Evaluation (DICONDE)**—a vendor-neutral digital data storage and transmission protocol that defines the organization of NDT image data and associated metadata in a standard electronic format.

**DISCUSSION—**

DICONDE is based on and inherits from the universally adopted medical standard, DICOM, which facilitates the interoperability of imaging equipment through data storage and network communication protocols.

**discontinuity, *n***—a lack of continuity or cohesion; an intentional or unintentional interruption in the physical structure or configuration of a material or component.

**evaluation**—determination of whether a relevant indication is cause to accept or to reject a material or component.

**examination, *n***—a procedure for determining a property (or properties) or other conditions or characteristics of a material or component by direct or indirect means.

**DISCUSSION—**

Examples include utilization of X-rays or ultrasonic waves for the purpose of determining (directly or by calculation) flaw content, density, or (for ultrasound) modulus; or detection of flaws by induction of eddy currents, observing thermal behavior, AE response, or utilization of magnetic particles or liquid penetrants.

**false indication, *n***—an NDT indication that is interpreted to be caused by a condition other than a discontinuity or imperfection.

**flaw, *n***—an imperfection or discontinuity that may be detectable by nondestructive testing and is not necessarily rejectable.

**flaw characterization, *n***—the process of quantifying the size, shape, orientation, location, growth, or other properties, of a flaw based on NDT response.

**imperfection, *n***—a departure of a quality characteristic from its intended condition.

**indication**—the response or evidence from a nondestructive examination.

**DISCUSSION—**

An indication is determined by interpretation to be relevant, non-relevant, or false.

**inspection, *n***—see **examination.**

**interpretation**—the determination of whether indications are relevant or nonrelevant.

**interpretation, *n***—the determination of whether indications are relevant, nonrelevant, or false.

*Nondestructive Evaluation*—see **Nondestructive Testing**.

*Nondestructive Examination*—see **Nondestructive Testing**.

*Nondestructive Inspection*—see **Nondestructive Testing**.

**Nondestructive Testing (NDT)**, *n*—the development and application of technical methods to examine materials or components in ways that do not impair future usefulness and serviceability in order to detect, locate, measure and evaluate flaws; to assess integrity, properties and composition; and to measure geometrical characteristics.

**nonrelevant indication**, *n*—an NDT indication that is caused by a condition or type of discontinuity that is not rejectable. False indications are non-relevant.

**reference standard**, *n*—a material or object for which all relevant chemical and physical characteristics are known and measurable, used as a comparison for, or standardization of, equipment or instruments used for nondestructive testing. (See also **standardization, instrument**.)

**relevant indication**, *n*—an NDT indication that is caused by a condition or type of discontinuity that requires evaluation.

**standard**—(1) a physical reference used as a basis for comparison or calibration; (2) a concept that has been established by authority, custom, or agreement to serve as a model or rule in the measurement of quality or the establishment of a practice or procedure.

**standardization, instrument**, *n*—the adjustment of an NDT instrument using an appropriate reference standard, to obtain or establish a known and reproducible response. (This is usually done prior to an examination, but can be carried out anytime there is concern about the examination or instrument response.) (See also **calibration, instrument**.)

**test**, *n*—see preferred terms **examination** or **inspection**.

ASTM E1316-22a  
<https://standards.iteh.ai/catalog/standards/sist/9358dfd40617astm-e1316-22a>  
**Section B: Acoustic Emission (AE) Terms**  
 The terms defined in Section B are the direct responsibility of Subcommittee E07.04 on Acoustic Emission Method.

**acoustic emission (AE)**—the class of phenomena whereby transient stress/displacement waves are generated by the rapid release of energy from localized sources within a material, or the transient waves so generated.

DISCUSSION—

Acoustic emission is the recommended term for general use. Other terms that have been used in AE literature include: (1) stress wave emission, (2) microseismic activity, and (3) emission or acoustic emission with other qualifying modifiers.

*acoustic emission channel*—see **channel, acoustic emission**.

*acoustic emission count (emission count) (N)*—see **count, acoustic emission**.

*acoustic emission count rate*—see **count rate, acoustic emission (emission rate or count rate) (N')**.

*acoustic emission event*—see **event, acoustic emission**.

*acoustic emission event energy*—see **energy, acoustic event**.

**acoustic emission mechanism or acoustic emission source mechanism**—a dynamic process or combination of processes occurring within a material, generating acoustic emission events. AE source mechanisms can be subdivided into several categories: material and mechanical, macroscopic and microscopic, primary and secondary.

DISCUSSION—

Examples of macroscopic material AE source mechanisms in metals are incremental crack advancements, plastic deformation development and fracture

of inclusions. Friction and impacts are examples of mechanical AE. A crack advancement can be considered a primary AE mechanism while a resulting crack surface friction can be considered as a secondary AE mechanism.

*acoustic emission sensor*—see **sensor, acoustic emission**.

*acoustic emission signal amplitude*—see **signal amplitude, acoustic emission**.

*acoustic emission signal (emission signal)*—see **signal, acoustic emission**.

*acoustic emission signature (signature)*—see **signature, acoustic emission**.

*acoustic emission transducer*—see **sensor, acoustic emission**.

*acoustic emission waveguide*—see **waveguide, acoustic emission**.

**acousto-ultrasonics (AU)**—a nondestructive examination method that uses induced stress waves to detect and assess diffuse defect states, damage conditions, and variations of mechanical properties of a test structure. The AU method combines aspects of acoustic emission (AE) signal analysis with ultrasonic materials characterization techniques.

**active source**—one which exhibits increasing cumulative AE activity with increasing or constant stimulus.

**adaptive location**—source location by iterative use of simulated sources in combination with computed location.

**AE activity, *n***—the presence of acoustic emission during a test.

*AE amplitude*—see **dB<sub>AE</sub>**.

**AE rms, *n***—the rectified, time averaged AE signal, measured on a linear scale and reported in volts.

**AE signal duration**—the time between AE signal start and AE signal end.

<https://standards.iteh.ai/catalog/standards/sist/446eda4f-e974-4b4f-9ff7-9358dfd4061f/astm-e1316-22a>

**AE signal end**—the recognized termination of an AE signal, usually defined as the last crossing of the threshold by that signal.

**AE signal generator**—a device which can repeatedly induce a specified transient signal into an AE instrument.

**AE signal rise time**—the time between AE signal start and the peak amplitude of that AE signal.

**AE signal start**—the beginning of an AE signal as recognized by the system processor, usually defined by an amplitude excursion exceeding threshold.

**AE source intensity**—average energy, counts or amplitude per hit.

**array, *n***—a group of two or more AE sensors positioned on a structure for the purposes of detecting and locating sources. The sources would normally be within the array.

*arrival time interval ( $\Delta t_{ij}$ )*—see **interval, arrival time**.

**attenuation, *n***—the gradual loss of acoustic emission wave energy as a function of distance through absorption, scattering, diffraction and geometric spreading.

DISCUSSION—

Attenuation can be measured as the decrease in AE amplitude or other AE signal parameter per unit distance.

**average signal level,  $n$** —the rectified, time averaged AE logarithmic signal, measured on the AE amplitude logarithmic scale and reported in  $\text{dB}_{\text{ac}}$  units (where  $0 \text{ dB}_{\text{ac}}$  refers to  $1 \mu\text{V}$  at the preamplifier input).

**broadband or wideband AE sensor**—an AE sensor which, when calibrated in accordance with Test Method E1106 or Practice E1781, exhibits a displacement or velocity response over several hundred kHz with a coefficient of variation of the response in  $\text{V/m}$  or  $\text{V/m/s}$  that does not exceed 50 %.

*burst emission*—see **emission, burst**.

**channel, acoustic emission**—an assembly of a sensor, preamplifier or impedance matching transformer, filters secondary amplifier or other instrumentation as needed, connecting cables, and detector or processor.

**DISCUSSION**—

A channel for examining fiberglass reinforced plastic (FRP) may utilize more than one sensor with associated electronics. Channels may be processed independently or in predetermined groups having similar sensitivity and frequency characteristics.

*continuous emission*—see **emission, continuous**.

**count, acoustic emission (emission count) ( $N$ )**—the number of times the acoustic emission signal exceeds a preset threshold during any selected portion of a test.

**count, event ( $N_e$ )**—the number obtained by counting each discerned acoustic emission event once.

**count rate, acoustic emission (emission rate or count rate) ( $N'$ )**—the time rate at which emission counts occur.

*count, ring-down*—see **count, acoustic emission**, the preferred term.

**couplant**—a material used at the structure-to-sensor interface to improve the transmission of acoustic energy across the interface during acoustic emission monitoring.

**critically active source**—one which exhibits an increasing rate of change of cumulative AE activity with increasing or constant stimulus.

**critically intense source**—one in which the AE source intensity consistently increases with increasing stimulus or with time under constant stimulus.

*cumulative (acoustic emission) amplitude distribution  $F(V)$* —see **distribution, amplitude, cumulative**.

*cumulative (acoustic emission) threshold crossing distribution  $F_t(V)$* —see **distribution, threshold crossing, cumulative**.

**$\text{dB}_{\text{AE}}$** —a logarithmic measure of acoustic emission signal amplitude, referenced to  $1 \mu\text{V}$  at the sensor, before amplification.

$$\text{Signal peak amplitude } (\text{dB}_{\text{AE}}) = (\text{dB}_{1\mu\text{V at sensor}}) = 20 \log_{10}(A_1/A_0) \quad (1)$$

where:

$A_0$  =  $1 \mu\text{V}$  at the sensor (before amplification), and

$A_1$  = peak voltage of the measured acoustic emission signal (also before amplification).

Acoustic Emission Reference Scale:

$\text{dB}_{\text{AE}}$ Value	Voltage at Sensor
0	1 $\mu\text{V}$
20	10 $\mu\text{V}$
40	100 $\mu\text{V}$
60	1 mV
80	10 mV
100	100 mV

DISCUSSION—

In the case of sensors with integral preamplifiers, the  $A_0$  reference is before internal amplification.

**dead time**—any interval during data acquisition when the instrument or system is unable to accept new data for any reason.

*differential (acoustic emission) amplitude distribution  $F(V)$* —see **distribution, differential (acoustic emission) amplitude  $f(V)$** .

*differential (acoustic emission) threshold crossing distribution  $f_t(V)$* —see **distribution, differential (acoustic emission) threshold crossing**.

**distribution, amplitude, cumulative (acoustic emission)  $F(V)$** —the number of acoustic emission events with signals that exceed an arbitrary amplitude as a function of amplitude  $V$ .

**distribution, threshold crossing, cumulative (acoustic emission)  $F_t(V)$** —the number of times the acoustic emission signal exceeds an arbitrary threshold as a function of the threshold voltage ( $V$ ).

**distribution, differential (acoustic emission) amplitude  $f(V)$** —the number of acoustic emission events with signal amplitudes between amplitudes of  $V$  and  $V + \Delta V$  as a function of the amplitude  $V$ .  $f(V)$  is the absolute value of the derivative of the cumulative amplitude distribution  $F(V)$ .

**distribution, differential (acoustic emission) threshold crossing  $f_t(V)$** —the number of times the acoustic emission signal waveform has a peak between thresholds  $V$  and  $V + \Delta V$  as a function of the threshold  $V$ .  $f_t(V)$  is the absolute value of the derivative of the cumulative threshold crossing distribution  $F_t(V)$ .

**distribution, logarithmic (acoustic emission) amplitude  $g(V)$** —the number of acoustic emission events with signal amplitudes between  $V$  and  $\alpha V$  (where  $\alpha$  is a constant multiplier) as a function of the amplitude. This is a variant of the differential amplitude distribution, appropriate for logarithmically windowed data.

**dynamic range**—the difference, in decibels, between the overload level and the minimum signal level (usually fixed by one or more of the noise levels, low-level distortion, interference, or resolution level) in a system or sensor.

**effective velocity,  $n$** —velocity calculated on the basis of arrival times and propagation distances determined by artificial AE generation; used for computed location.

**emission, burst**—a qualitative description of an individual emission event resulting in a discrete signal.

DISCUSSION—

Fig. 1 shows an oscilloscope trace of burst emission signals on a background of continuous emission signal.

**emission, continuous**—a qualitative description of emission producing a sustained signal as a result of time overlapping or successive emission events from one or several sources, or both.

DISCUSSION—

Fig. 2 and Fig. 3 show oscilloscope traces of continuous emission signals at two different sweep rates.

**energy, acoustic emission event**—the total elastic energy released by an emission event.

**energy, acoustic emission signal**—the energy contained in an acoustic emission signal, which is evaluated as the integral of the volt-squared function over time.



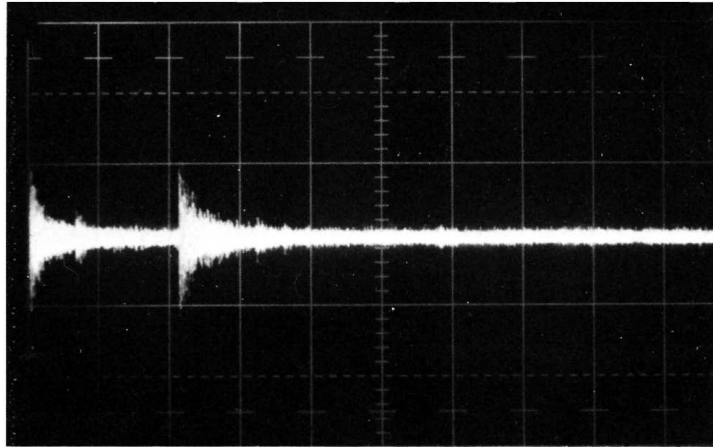


FIG. 1 Burst Emission Signal on a Continuous Emission Signal Background (Sweep Rate—5 ms/cm)

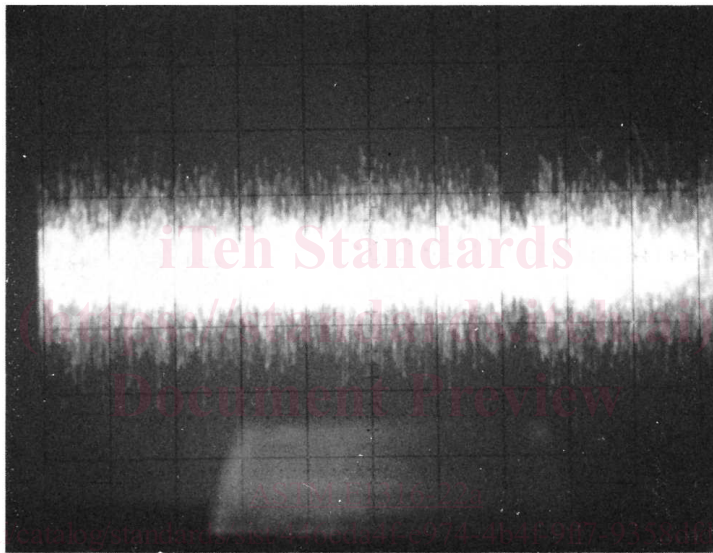


FIG. 2 Continuous Emission Signal (Sweep Rate—5 ms/cm)

**evaluation threshold**—a threshold value used for analysis of the examination data. Data may be recorded with a *system examination threshold* lower than the *evaluation threshold*. For analysis purposes, dependence of measured data on the *system examination threshold* must be taken into consideration.

**event, acoustic emission (emission event)**—an occurrence of a local material change or mechanical action resulting in acoustic emission.

*event count (N<sub>e</sub>)*—see **count, event**.

*event count rate (Ṅ<sub>e</sub>)*—see **rate, event count**.

**examination area (examination region)**—that portion of a structure, or test article, being examined using acoustic emission technology.

**Felicity effect**—the presence of detectable acoustic emission at a fixed predetermined sensitivity level at stress levels below those previously applied.



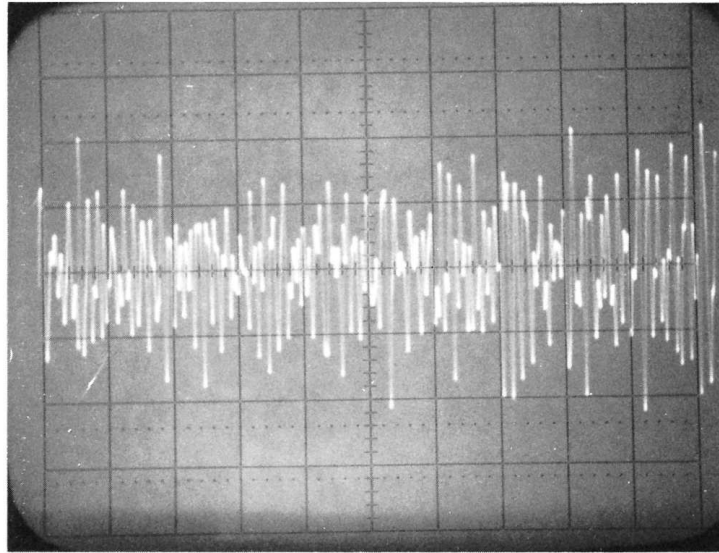


FIG. 3 Continuous Emission Signal (Sweep Rate—0.1 ms/cm)

**Felicity ratio**—the ratio of the stress at which acoustic emission is detected, to the previously applied maximum stress.

DISCUSSION—

The fixed sensitivity level will usually be the same as was used for the previous loading or examination.

**first hit location**—a zone location method defined by which a channel among a group of channels first detects the signal.

**floating threshold**—any threshold with amplitude established by a time average measure of the input signal.

**hit**—the detection and measurement of an AE signal on a channel.

**instrumentation dead time**—see **dead time, instrumentation**.

**intense source**—one in which the AE source intensity of an active source consistently exceeds, by a specified amount, the average AE source intensity of active sources.

**interval, arrival time ( $\Delta t_{ij}$ )**—the time interval between the detected arrivals of an acoustic emission wave at the *i*th and *j*th sensors of a sensor array.

**Kaiser effect**—the absence of detectable acoustic emission at a fixed sensitivity level, until previously applied stress levels are exceeded.

DISCUSSION—

Whether or not the effect is observed is material specific. The effect usually is not observed in materials containing developing flaws.

**location accuracy, *n***—a value determined by comparison of the actual position of an AE source (or simulated AE source) to the computed location.

**location, cluster, *n***—a location technique based upon a specified amount of AE activity located within a specified length or area, for example: 5 events within 12 linear inches or 12 square inches.

**location, computed, *n***—a source location method based on algorithmic analysis of the difference in arrival times among sensors.

DISCUSSION—

Several approaches to computed location are used, including linear location, planar location, three dimensional location, and adaptive location.

- (a) *linear location, n*—one dimensional source location requiring two or more channels.
- (b) *planar location, n*—two dimensional source location requiring three or more channels.
- (c) *3D location, n*—three dimensional source location requiring five or more channels.
- (d) *adaptive location, n*—source location by iterative use of simulated sources in combination with computed location.

**location, continuous AE signal, n**—a method of location based on continuous AE signals, as opposed to hit or difference in arrival time location methods.

DISCUSSION—

This type of location is commonly used in leak location due to the presence of continuous emission. Some common types of continuous signal location methods include signal attenuation and correlation analysis methods.

- (a) *signal attenuation-based source location, n*—a source location method that relies on the attenuation versus distance phenomenon of AE signals. By monitoring the AE signal magnitudes of the continuous signal at various points along the object, the source can be determined based on the highest magnitude or by interpolation or extrapolation of multiple readings.
- (b) *correlation-based source location, n*—a source location method that compares the changing AE signal levels (usually waveform based amplitude analysis) at two or more points surrounding the source and determines the time displacement of these signals. The time displacement data can be used with conventional hit based location techniques to arrive at a solution for the source site.

**location, source, n**—any of several methods of evaluating AE data to determine the position on the structure from which the AE originated. Several approaches to source location are used, including zone location, computed location, and continuous location.

**location, zone, n**—any of several techniques for determining the general region of an acoustic emission source (for example, total AE counts, energy, hits, and so forth).

DISCUSSION—

Several approaches to zone location are used, including independent channel zone location, first hit zone location, and arrival sequence zone location.

- (a) *independent channel zone location, n*—a zone location technique that compares the gross amount of activity from each channel.
- (b) *first-hit zone location, n*—a zone location technique that compares only activity from the channel first detecting the AE event.
- (c) *arrival sequence zone location, n*—a zone location technique that compares the order of arrival among sensors.

*logarithmic (acoustic emission) amplitude distribution g(V)*—see **distribution, logarithmic (acoustic emission) amplitude**.

**overload recovery time**—an interval of nonlinear operation of an instrument caused by a signal with amplitude in excess of the instrument's linear operating range.

[ASTM E1316-22a](https://standards.iteh.ai/ASTM-E1316-22a)

<https://standards.iteh.ai/catalog/standards/sist/446eda4f-e974-4b4f-9ff7-9358dfd4061f/astm-e1316-22a>

*performance check, AE system*—see **verification, AE system**.

**processing capacity**—the number of hits that can be processed at the processing speed before the system must interrupt data collection to clear buffers or otherwise prepare for accepting additional data.

**processing speed**—the sustained rate (hits/s), as a function of the parameter set and number of active channels, at which AE signals can be continuously processed by a system without interruption for data transport.

**rate, event count (N'e)**—the time rate of the event count.

*rearm delay time*—see **time, rearm delay**.

**resonant or narrowband AE sensor**—an AE sensor which, when calibrated in accordance with Test Method E1106 or Practice E1781, exhibits a displacement or velocity response with one or more dominant frequency peaks such that it does not satisfy the definition of a broadband AE sensor.

*ring-down count*—see **count, acoustic emission, the preferred term**.

**sensor, acoustic emission**—a detection device, generally piezoelectric, that transforms the particle motion produced by an elastic wave into an electrical signal.

**signal, acoustic emission (emission signal)**—an electrical signal obtained by detection of one or more acoustic emission events.

**signal amplitude, acoustic emission**—the peak voltage of the largest excursion attained by the signal waveform from an emission event.

**signal overload level**—that level above which operation ceases to be satisfactory as a result of signal distortion, overheating, or damage.

**signal overload point**—the maximum input signal amplitude at which the ratio of output to input is observed to remain within a prescribed linear operating range.

**signal strength**—the measured area of the rectified AE signal with units proportional to volt-sec.

DISCUSSION—

The proportionality constant is specified by the AE instrument manufacturer.

**signature, acoustic emission (signature)**—a characteristic set of reproducible attributes of acoustic emission signals associated with a specific test article as observed with a particular instrumentation system under specified test conditions.

**stimulation**—the application of a stimulus such as force, pressure, heat, and so forth, to a test article to cause activation of acoustic emission sources.

**system examination threshold**—the electronic instrument threshold (see **evaluation threshold**) which data will be detected.

*transducers, acoustic emission*—see **sensor, acoustic emission**.

**verification, AE system (performance check, AE system)**—the process of testing an AE system to assure conformance to a specified level of performance or measurement accuracy. (This is usually carried out prior to, during or after, or combinations thereof, an AE examination with the AE system connected to the examination object, using a simulated or artificial acoustic emission source.)

**voltage threshold**—a voltage level on an electronic comparator such that signals with amplitudes larger than this level will be recognized. The voltage threshold may be user adjustable, fixed, or automatic floating.

**waveguide, acoustic emission**—a device that couples elastic energy from a structure or other test object to a remotely mounted sensor during AE monitoring. An example of an acoustic emission waveguide would be a solid wire or rod that is coupled at one end to a monitored structure, and to a sensor at the other end.

**wideband-based (modal) AE techniques**—AE techniques with wideband AE sensors that subject waveforms of the signals to combined time and frequency analysis to obtain mode-based arrival times (for source location calculations) and modal amplitudes for potential source identification. Note that mode-based arrival times can also be obtained with resonant sensors, but only at certain experimentally determined frequencies.

### **Section C: Electromagnetic Testing (ET) Terms**

The terms defined in Section C are the direct responsibility of Subcommittee E07.07 on Electromagnetic Methods.

**absolute coil**—a coil (or coils) that respond(s) to the total detected electric or magnetic properties, or both, of a part or section of the part without comparison to another section of the part or to another part.

**absolute measurements**—measurements made without a direct reference using an absolute coil in contrast to differential and comparative measurements. (See also **absolute coil**).

**absolute readout**—the signal output of an absolute coil. (See also **absolute coil**.)

**absolute system**—a system that uses a coil assembly and associated electronics to measure the total electromagnetic properties of a part without direct comparison to another section of the part or to another part (see **absolute coil**.)

**acceptance level**—a level above or below which specimens are acceptable in contrast to rejection level.

**acceptance limits**—levels used in electromagnetic sorting which establish the group into which the material under examination belongs.

*amplitude distortion*—same as **harmonic distortion**.

**amplitude response**—that property of an examination system whereby the amplitude of the detected signal is measured without regard to phase. (See also **harmonic analysis and phase analysis**.)

**annular coil clearance**—the mean radial distance between adjacent coil assembly and part surface in electromagnetic encircling coil examination.

*annular coils*—see **encircling coils**.

**artificial discontinuity**—reference discontinuities, such as holes, grooves, or notches, that are introduced into a reference standard to provide accurately reproducible sensitivity levels for electromagnetic test equipment.

**band pass filter**—a wave filter having a single transmission band; neither of the cut-off frequencies being zero or infinity.

*bobbin coil*—see **ID coil**.

*bucking coils*—same as **differential coils**.

*circumferential coils*—see **encircling coils**.

*coil, absolute*—see **absolute coil**.

*coil, reference*—see **reference coil**.

**coil size**—the dimension of a coil, for example, length or diameter.

**coil spacing**—the axial distance between two encircling coils of a differential system.

**coil, test**—the section of the probe or coil assembly that excites or detects, or both, the electromagnetic field in the material under examination.

**comparative measurements**—measurements made in which the unbalance in the system is measured using comparator coils in contrast to differential and absolute measurements. (See also **comparator coils**.)

**comparative readout**—the signal output of comparator coils. (See also **comparator coils**.)

**comparative system**—a system that uses coil assemblies and associated electronics to detect any electric or magnetic condition, or both, that is not common to the specimen and the standard (see **comparator coils**).

**comparator coils**—two or more coils electrically connected in series opposition but arranged so that there is no mutual induction (coupling) between them such that any electric or magnetic condition, or both, that is not common to the specimen and the standard, will produce an unbalance in the system and thereby yield an indication.

**conductivity**—the intrinsic property of a particular material to carry electric current; it is commonly expressed in percent IACS (International Annealed Copper Standard) or MS/m (MegaSiemens/metre).

**conformable**—refers to an ability of sensors or sensor arrays to conform to non-planar surfaces without significant effects on the measurement results, or with effects that are limited to a quantifiable bound.

**coupling**—two electric circuits are said to be coupled to each other when they have an impedance in common so that a current in one causes a voltage in the other.

*cut-off level*—same as **rejection level**.

**defect resolution**—a property of an examination system that enables the separation of indications due to defects in a sample that are located in proximity to each other.

**depth of penetration**—the depth at which the magnetic field strength or intensity of induced eddy currents has decreased to 37 % of its surface value. The depth of penetration depends upon the coil size, the frequency of the signal, and the conductivity and permeability of the material. It is related to the coil size at low frequencies and is equal to the skin depth at high frequencies. Related synonymous terms are standard depth of penetration and skin depth. (See also **skin effect**.)

**depth of sensitivity**—depth to which the sensor response to features or properties of interest exceeds a noise threshold.

DISCUSSION—

The depth of sensitivity can be larger or smaller than the depth of penetration since it incorporates a comparison between the signal obtained from a feature as well as measurement noise, whereas the depth of penetration refers to the decrease in field intensity with distance away from a test coil.

**diamagnetic material**—a material whose relative permeability is less than unity.

DISCUSSION—

The intrinsic induction  $B_i$  is oppositely directed to the applied magnetizing force  $H$ .

**differential coils**—two or more coils electrically connected in series opposition such that any electric or magnetic condition, or both, that is not common to the areas of a specimen being electromagnetically examined will produce an unbalance in the system and thereby yield an indication.

**differential measurements**—measurements made in which the imbalance in the system is measured using differential coils in contrast to absolute and comparative measurements. (See also **differential coils**.)

**differential readout**—the signal output of differential coils. (See also **differential coils**.)

**differential signal**—an output signal that is proportional to the rate of change of the input signal.

**differential system**—an electromagnetic examination system that uses coil assemblies and associated electronics to detect an electric or magnetic condition, or both, that is not common to the areas of the specimen being examined. (See also **differential coils**.)

**drive winding**—a conductor pattern or coil that produces a magnetic field that couples to the material being examined.

**DISCUSSION—**

The drive winding can have various geometries, including: (1) a simple linear conductor that is placed adjacent to a one-dimensional array of sensing elements; (2) one or multiple conducting loops driven to create a complex field pattern; and (3) multiple conducting loops with a separate loop for each sensing element.

**eddy current**—an electrical current caused to flow in a conductor by the time or space variation, or both, of an applied magnetic field.

**eddy current testing**—a nondestructive testing method in which eddy current flow is induced in the material under examination.

**DISCUSSION—**

Changes in the flow caused by variations in the specimen are reflected into a nearby coil, coils, Hall effect device, magnetoresistive sensor or other magnetic field sensor for subsequent analysis by suitable instrumentation and techniques.

**edge effect**—the disturbance of the magnetic field and eddy-currents due to the proximity of an abrupt change in specimen geometry (edge). This effect generally results in the masking of discontinuities within the affected region. (This effect is also termed the **end effect**.)

**effective depth of penetration (EDP)**—for (a) thickness, the minimum depth beyond which an examination system can no longer reliably detect a further increase in specimen thickness, or (b) defects, the limit for reliably detecting metallurgical or mechanical discontinuities by way of conventional continuous wave (CW) eddy current instrumentation and sensors. The EDP point is approximately three times the standard depth of penetration.

**effective permeability**—a hypothetical quantity that describes the magnetic permeability that is experienced under a given set of physical conditions such as a cylindrical specimen in an encircling coil at a specific frequency. This quantity may be different from the permeability of the particular metal being examined in that it takes into account such things as the geometry of the part, the relative position of the encircling coil, and characteristics of the magnetic field.

**electrical center**—the center established by the electromagnetic field distribution within a test coil. A constant intensity signal, irrespective of the circumferential position of a discontinuity, is indicative of electrical centering. The electrical center may be different from the physical center of the test coil. [ASTM E1316-22a](https://standards.iteh.ai/catalog/standards/sist/446eda4f-e974-4b4f-9ff7-9358dfd4061f/astm-e1316-22a)

<https://standards.iteh.ai/catalog/standards/sist/446eda4f-e974-4b4f-9ff7-9358dfd4061f/astm-e1316-22a>

**electromagnetic testing**—a nondestructive test method for materials, including magnetic materials, that uses electromagnetic energy having frequencies less than those of visible light to yield information regarding the quality of examined material.

**encircling coils**—coil(s) or coil assembly that surround(s) the part to be examined. Coils of this type are also referred to as annular, circumferential, or feed-through coils.

*end effect*—see **edge effect**.

**end effect**—the loss in sensitivity to discontinuities located near the extreme ends of the tube as the ends of the tube enter or leave the test coil.

*feed-through coils*—see **encircling coils**.

**ferromagnetic material**—a material that, in general, exhibits the phenomena of magnetic hysteresis and saturation, and whose permeability is dependent on the magnetizing force.

**fill factor**—(a) for encircling coil electromagnetic testing, the ratio of the cross-sectional area of the specimen to the effective cross-sectional core area of the primary encircling coil (outside diameter of coil form, not inside diameter which is adjacent to specimen); (b) for internal probe electromagnetic testing, the ratio of the effective cross-sectional area of the primary internal probe coil to the cross-sectional area of the tube interior.



**filter**—a network that passes electromagnetic wave energy over a described range of frequencies and attenuates energy at all other frequencies.

*gate*—same as **rejection level**.

**harmonic analysis**—an analytical technique whereby the amplitude or phase, or both, of the frequency components of a complex periodic signal is determined.

**harmonic distortion**—nonlinear distortion characterized by the appearance in the output of harmonics other than the fundamental component when the input wave is sinusoidal.

**IACS**—the International Annealed Copper Standard; an international standard of electrical conductivity.

**ID coil**—a coil or coil assembly used for electromagnetic testing by insertion into the examination piece as in the case of an inside probe for tubing. Coils of this type are also referred to as inside coils, inserted coils, or bobbin coils.

**impedance**—the total opposition that a circuit presents to the flow of an alternating current, specifically the complex quotient of voltage divided by current.

**impedance analysis**—an analytical method that consists of correlating changes in the amplitude, phase, or quadrature components, or all of these, of a complex signal voltage to the electromagnetic conditions within a specimen.

**impedance plane diagram**—a graphical representation of the locus of points, indicating the variations in the impedance of a test coil as a function of basic examination parameters.

**incremental permeability**—the ratio of the change in magnetic induction to the corresponding change in magnetizing force when the mean induction differs from zero.

[ASTM E1316-22a](https://standards.iteh.ai/ASTM-E1316-22a)

<https://standards.iteh.ai/catalog/standards/sist/446eda4f-e974-4b4f-9ff7-9358dfd4061f/astm-e1316-22a>

**initial permeability**—the slope of the induction curve at zero magnetizing force as the specimen is being removed from a demagnetizing condition (slope at origin of BH curve before hysteresis is observed).

*inserted coil*—see **ID coil**.

*inside coil*—see **ID coil**.

**insulating shims**—conformable and substantially non-conducting or insulating foils that are used to measure effects of small lift-off excursions on sensor response.

**lift-off**—normal distance from the plane of the sensor coil or winding conductors to the surface of the conducting material under examination.

**lift-off effect**—the effect observed in an examination system output due to a change in magnetic coupling between a specimen and a probe coil whenever the distance between them is varied.

**magnetic history**—magnetic condition of a ferromagnetic part under examination based on previous exposures to magnetic fields.

**magnetic leakage flux**—the excursion of magnetic lines of force from the surface of a specimen.